Sunday 2004 Tutorial Program

<table>
<tr><th></th><th>General Reliability</th><th>ESD</th><th>High K Dielectric</th><th>NBTI</th><th></th></tr>
<tr><td>AM1</td><td rowspan="2">101. Introduction to Reliability
V. Reddy
TI</td><td rowspan="3">121. ESD & Latchup in Advanced Technologies
S. Voldman
IBM</td><td>131. Mat. Prop. And Local Phen. In High K Dielectrics
Glen Wilk
ASM America</td><td>141. NBTI: Physics, Materials & Process Issues
D. Schroder
ASU</td><td></td></tr>
<tr><td>AM2</td><td rowspan="2">132. Interfacial Reaction & Stability of High K Dielectrics & Metals
R. Wallace
U.T. Dallas</td><td>142. Device and Circuit Issues
A. Krishnam
TI</td><td></td></tr>
<tr><td></td><td>Design Practices</td><td>SER</td><td>Vendors</td></tr>
<tr><td>PM1</td><td>111. Product Rel. Challenges for VLSI Tech.
R. Bolam, IBM</td><td>122. ESD Protection Design in CMOS
T. Maloney
Intel</td><td>133. Deposition & Defect Characterization of High K Mat
J. Conley, Sharp</td><td>151. Intro to SER and Testing Challenges
R. Velazco
TIMA</td><td rowspan="3">160. Vendor Presentations</td></tr>
<tr><td rowspan="2">PM2</td><td rowspan="2">112. Effect of Rel. Mech. On VLSI Circuit Function
W. Ellis, IBM</td><td rowspan="2">123. ESD Testing: HBM to vf-TLP
H. Gieser
Fraunhofer IZM</td><td rowspan="2">134. Defect Transport of High K Dielectrics
Ed Cartier
IBM</td><td>152. Software Approaches to Mitigating SERs
F. Faure TIMA</td></tr>
<tr><td>153. Eval. SERs in FPGAs
M. Wirthlin BYU</td></tr>
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